



Single Event Radiation Hardened High Speed, Current Mode PWM

IS-1845ASRH, IS-1845ASEH



The IS-1845ASRH, IS-1845ASEH are designed to be used in switching power supplies operating in current-mode. The rising edge of the on-chip oscillator turns on the output.

Turn-off is controlled by the current sense comparator and occurs when the sensed current reaches a peak controlled by the error amplifier.

Constructed with Intersil's Rad Hard Silicon Gate (RSG) dielectrically isolated BiCMOS process, these devices are immune to single event latch-up and have been specifically designed to provide a high level of immunity to single event transients. All specified parameters are guaranteed and tested for 300krad(Si) total dose performance at a high dose rate and 50krad(Si) total dose at a low dose rate.

Detailed Electrical Specifications for these devices are contained in the SMD <u>5962-01509</u>. A "hot-link" is also provided on our website for downloading the SMD.

Features

- Electrically Screened to DSCC SMD # 5962-01509
- QML Qualified per MIL-PRF-38535 Requirements
- Radiation Environment

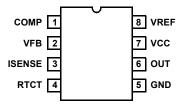
- High Dose Rate	.300 krad(SI) (Max)
- Low Dose Rate	50 krad(SI) (Max)
- SEL Immune	ielectrically Isolated
- SEU Immune	35MeV/mg/cm ²
- SEU Cross-Section at 89MeV/mg/cm ²	² 5 x 10 ⁻⁶ cm ²
Low Start-up Current	100μA (Typ)
Fast Propagation Delay	80ns (Typ)
Supply Voltage Range	12V to 20V
High Output Drive	1A (Peak, Typ)
Undervoltage Lockout 8.8V Start (Typ), 8.2V Stop (Typ)

Applications

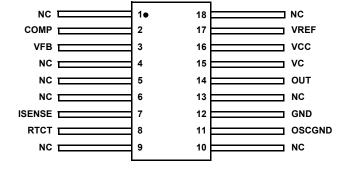
- Current-Mode Switching Power Supplies
- · Control of High Current FET Drivers
- Motor Speed and Direction Control

Pin Configurations

IS7-1845ASRH, IS7-1845ASEH (8 LD CDIP2-T8 SBDIP) TOP VIEW



IS9-1845ASRH, IS9-1845ASEH (18 LD FLATPACK) TOP VIEW



NOTES:

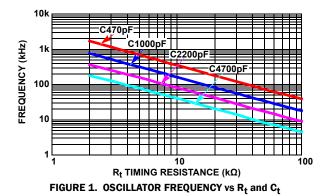
- 1. Grounding the COMP pin does not inhibit the output. The output may be inhibited by applying >1.2V to the ISENSE pin.
- 2. This part should be operated with C_t = 3.3nF and R_t = 10k timing components only.

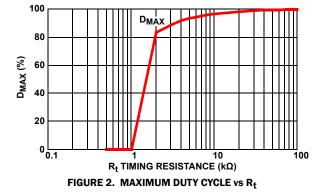
IS-1845ASRH, IS-1845ASEH

Ordering Information

ORDERING NUMBER	INTERNAL MKT. NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. DWG. #
5962F0150901V9A	ISO-1845ASRH-Q	-50 to +125	Die	
5962F0150902V9A	ISO-1845ASEH-Q	-50 to +125	Die	
ISO-1845ASRH/Sample	ISO-1845ASRH/SAMPLE	-50 to +125	Die	
5962F0150901VPC	IS7-1845ASRH-Q	-50 to +125	8 Ld SBDIP	D8.3
5962F0150902VPC	IS7-1845ASEH-Q	-50 to +125	8 Ld SBDIP	D8.3
5962F0150901QPC	IS7-1845ASRH-8	-50 to +125	8 Ld SBDIP	D8.3
5962F0150901VXC	IS9-1845ASRH-Q	-50 to +125	18 Ld Flatpack	K18.B
5962F0150902VXC	IS9-1845ASEH-Q	-50 to +125	18 Ld Flatpack	K18.B
5962F0150901QXC	IS9-1845ASRH-8	-50 to +125	18 Ld Flatpack	K18.B
IS7-1845ASRH/Proto	IS7-1845ASRH/PROTO	-50 to +125	8 Ld SBDIP	D8.3
IS9-1845ASRH/Proto	IS9-1845ASRH/PROTO	-50 to +125	18 Ld Flatpack	K18.3

Typical Performance Curves





IS-1845ASRH, IS-1845ASEH

Die Characteristics

DIE DIMENSIONS

 $3090\mu m \ x \ 4080\mu m \ (121.6 \ mils \ x \ 159.0 \ mils)$ Thickness: $483\mu m \pm 25.4\mu m \ (19 \ mils \pm 1 \ mil)$

INTERFACE MATERIALS

Glassivation

Type: Phosphorus Silicon Glass (PSG)

Thickness: 8.0kA ± 1.0kA

Top Metallization

Type: AlSiCu

Thickness: 16.0kA ± 2kA

Substrate

Radiation Hardened Silicon Gate,

Dielectric Isolation

Backside Finish

Silicon

ASSEMBLY RELATED INFORMATION

Substrate Potential

Unbiased (DI)

ADDITIONAL INFORMATION

Worst Case Current Density

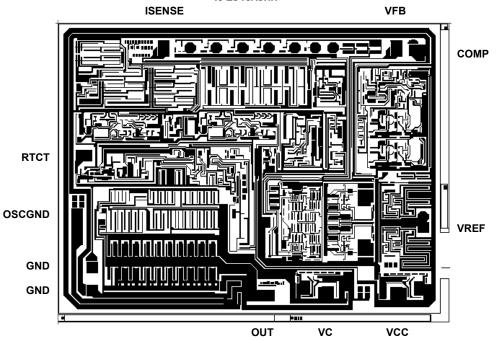
 $< 2.0 \times 10^5 \text{ A/cm}^2$

Transistor Count

582

Metallization Mask Layout

IS-1845ASRH



NOTES:

- 3. Both the GND pads must be bonded to ground.
- 4. The OUT double-sized bond pad must be double bonded for current sharing purposes.
- 5. The OSCGND double-sized bond pad must be double bonded to ground for current sharing purposes.

For additional products, see www.intersil.com/product-tree

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